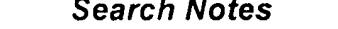


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/710,423	HELLER ET AL.
	Examiner	Art Unit
	Benjamin Huh	3767

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner